



Contacts:

Aehr Test Systems

Greg Perkins

V.P. Worldwide Sales & Service

(510) 623-9400 x241

**AEHR TEST SYSTEMS RECEIVES FOLLOW-ON ORDER FOR ITS
NEW ADVANCED BURN-IN AND TEST SYSTEM (ABTS™) FROM
INTEGRATED SERVICE TECHNOLOGY IN TAIWAN**

Fremont, CA (July 14, 2009) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received a follow-on order for the Company's new Advanced Burn-in and Test System (ABTS) from Integrated Service Technology (iST) in Taiwan. The system is configured for burning-in and testing advanced logic devices. This order follows successful use of the first system over the last several months. The system is expected to ship to iST's Shanghai facility within the next three months.

"We are pleased to have received this follow-on order from our first ABTS customer," said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. "We believe this order confirms the quality and cost-effectiveness of the ABTS for production burn-in and test of packaged ICs."

The ABTS family of products is based on a completely new hardware and software architecture that addresses not only today's devices, but also future devices for many years to come. The system can test and burn-in memory devices as well as both high and low-power logic devices. The ABTS system can be configured to provide individual device temperature control for devices up to 75W or more and with up to 320 I/O channels. It uses N+1 redundancy technology for many key components in the system to provide the highest possible system uptime.

Come see the new ABTS system in Aehr Test Systems' booth #430 at Semicon West in San Francisco at the Moscone Center, July 14 to 16.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS, FOX™, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices

simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

###